



POWER MOSFET THRU-HOLE (TO-254AA)

500V, N-CHANNEL REF: MIL-PRF-19500/592 HEXFET MOSFET TECHNOLOGY

Product Summary

Part Number	R _{DS(on)}	I _D	
IRFM450	0.415Ω	12A	



Description

HEXFET MOSFET technology is the key to IR HiRel advanced line of power MOSFET transistors. The efficient geometry design achieves very low on-state resistance combined with high trans conductance. HEXFET transistors also feature all of the well-established advantages of MOSFETs, such as voltage control, very fast switching, ease of paralleling and electrical parameter temperature stability. They are well-suited for applications such as switching power supplies, motor controls, inverters, choppers, audio amplifiers, high energy pulse circuits, and virtually any application where high reliability is required. The HEXFET transistor's totally isolated package eliminates the need for additional isolating material between the device and the heat sink. This improves thermal efficiency and reduces drain capacitance.

Features

- Simple Drive Requirements
- Ease of Paralleling
- · Hermetically Sealed
- · Electrically Isolated
- Dynamic dv/dt Rating
- Light Weight
- ESD Rating: Class 3A per MIL-STD-750, Method 1020

Absolute Maximum Ratings

	Parameter		Units
I _D @ V _{GS} = 10V, T _C = 25°C	Continuous Drain Current	12	
I _D @ V _{GS} = 10V, T _C = 100°C	Continuous Drain Current	8.0	Α
I _{DM}	Pulsed Drain Current ①	48	
P _D @T _C = 25°C	Maximum Power Dissipation	150	W
	Linear Derating Factor	1.2	W/°C
V _{GS}	Gate-to-Source Voltage	± 20	V
E _{AS}	Single Pulse Avalanche Energy ②	750	mJ
I _{AR}	Avalanche Current ①	12	Α
E _{AR}	Repetitive Avalanche Energy ①	15	mJ
dv/dt	Peak Diode Recovery dv/dt ③	3.5	V/ns
T _J	Operating Junction and	-55 to + 150	
T _{STG}	Storage Temperature Range		°C
	Lead Temperature	300 (0.063 in. /1.6 mm from case for 10s)	
	Weight	9.3 (Typical)	g

For Footnotes refer to the page 2.



Electrical Characteristics @ T_i = 25°C (Unless Otherwise Specified)

	Parameter	Min.	Тур.	Max.	Units	Test Conditions
BV _{DSS}	Drain-to-Source Breakdown Voltage	500			V	$V_{GS} = 0V, I_{D} = 1.0mA$
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.68		V/°C	Reference to 25°C, I _D = 1.0mA
R _{DS(on)}	Static Drain-to-Source On-State			0.415	Ω	V _{GS} = 10V, I _D = 8.0A ④
	Resistance			0.515	52	V _{GS} = 10V, I _D = 12A ④
$V_{GS(th)}$	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}$, $I_D = 250\mu A$
Gfs	Forward Transconductance	6.5			S	$V_{DS} = 15V, I_{D} = 8.0A$ ④
I _{DSS}	Zero Gate Voltage Drain Current			25	μA	$V_{DS} = 400V, V_{GS} = 0V$
	Zero Gate Voltage Brain Gurrent			250	μΛ	$V_{DS} = 400V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I_{GSS}	Gate-to-Source Leakage Forward			100	nA	V _{GS} = 20V
	Gate-to-Source Leakage Reverse			-100	ш	$V_{GS} = -20V$
Q_G	Total Gate Charge			120		I _D = 12A
Q_GS	Gate-to-Source Charge			19	nC	V _{DS} = 250V
Q_{GD}	Gate-to-Drain ('Miller') Charge			70		V _{GS} = 10V
t _{d(on)}	Turn-On Delay Time			35		$V_{DD} = 250V$
tr	Rise Time			190	20	I _D = 12A
$t_{d(off)}$	Turn-Off Delay Time			170	ns	$R_G = 2.35\Omega$
t _f	Fall Time			130		V _{GS} = 10V
Ls +L _D	Total Inductance		6.8		nH	Measured from Drain lead (6mm / 0.25 in from package) to Source lead (6mm/ 0.25 in from package) with Source wire internally bonded from Source pin to Drain pad
C _{iss}	Input Capacitance		2700			V _{GS} = 0V
Coss	Output Capacitance		600		pF	V _{DS} = 25V
C _{rss}	Reverse Transfer Capacitance		240			f = 1.0MHz

Source-Drain Diode Ratings and Characteristics

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	Parameter	Min.	Тур.	Max.	Units	Test Conditions
I _S	Continuous Source Current (Body Diode)			12	^	
I _{SM}	Pulsed Source Current (Body Diode) ①			48	А	
V_{SD}	Diode Forward Voltage			1.7	V	$T_J = 25^{\circ}C, I_S = 12A, V_{GS} = 0V$
t _{rr}	Reverse Recovery Time			1600	ns	$T_J = 25^{\circ}C, I_F = 12A, V_{DD} \le 50V$
Q _{rr}	Reverse Recovery Charge			14	μC	di/dt = 100A/µs ④
t _{on}	Forward Turn-On Time	Intrins	ic turn-c	on time i	s negligib	le (turn-on is dominated by L _S +L _D)

Thermal Resistance

	Parameter	Min.	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case			0.83	
R _{θCS}	Case -to-Sink		0.21		°C/W
$R_{\theta JA}$	Junction-to-Ambient (Typical socket mount)			48	

Footnotes:

- ① Repetitive Rating; Pulse width limited by maximum junction temperature.
- $^{\circ}$ V_{DD} = 50V, starting T_J = 25°C, L = 10.4mH, Peak I_L = 12A, V_{GS} = 10V
- $\label{eq:local_local_local} \text{\Im} \quad I_{SD} \leq 12A, \; di/dt \leq 130A/\mu s, \; V_{DD} \leq 500V, \; T_J \leq 150^{\circ}C$

④ Pulse width \leq 300 µs; Duty Cycle \leq 2%.

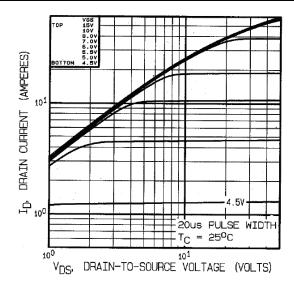


Fig 1. Typical Output Characteristics

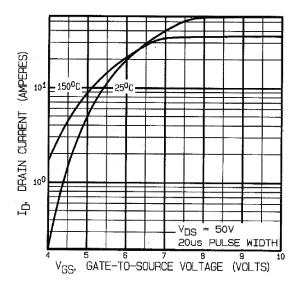


Fig 3. Typical Transfer Characteristics

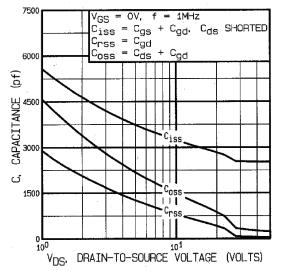


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

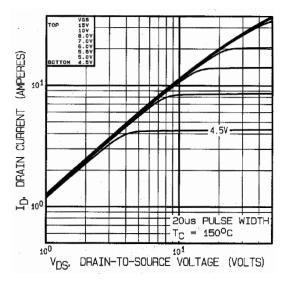


Fig 2. Typical Output Characteristics

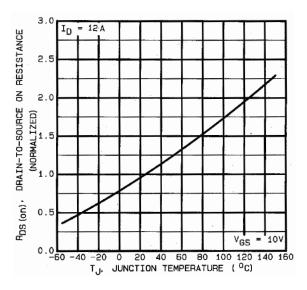


Fig 4. Normalized On-Resistance Vs. Temperature

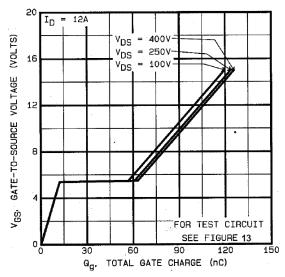


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

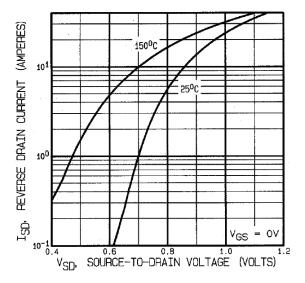


Fig 7. Typical Source-Drain Diode Forward Voltage

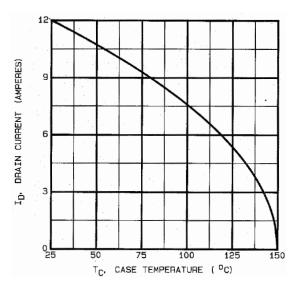


Fig 9. Maximum Drain Current Vs. Case Temperature

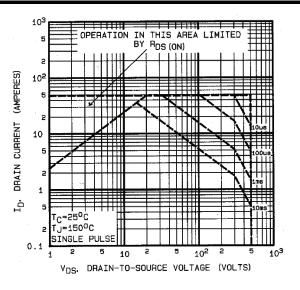


Fig 8. Maximum Safe Operating Area

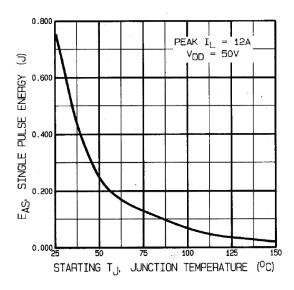


Fig 10. Maximum Avalanche Energy Vs. Drain Current

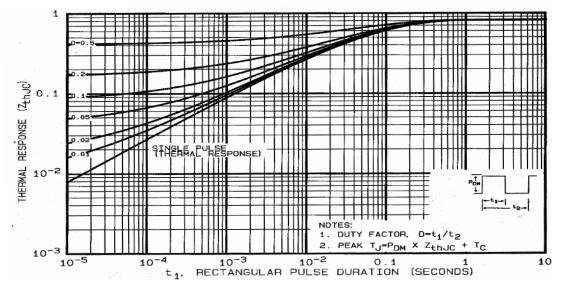


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

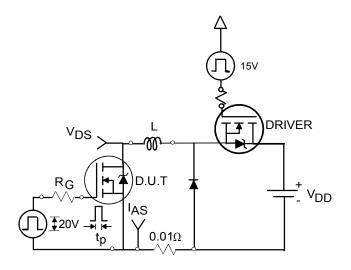


Fig 12a. Unclamped Inductive Test Circuit

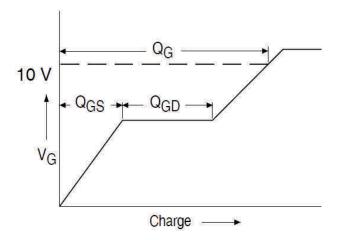


Fig 13a. Gate Charge Waveform

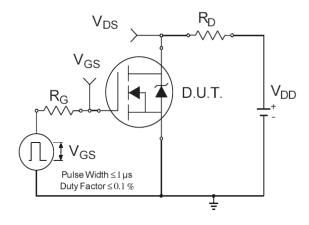


Fig 14a. Switching Time Test Circuit

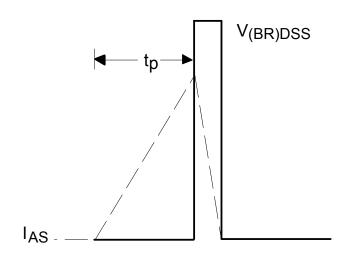


Fig 12b. Unclamped Inductive Waveforms

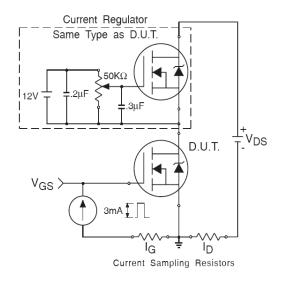


Fig 13b. Gate Charge Test Circuit

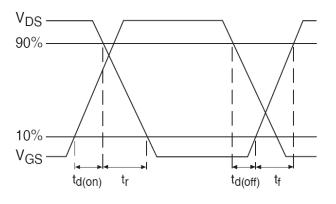
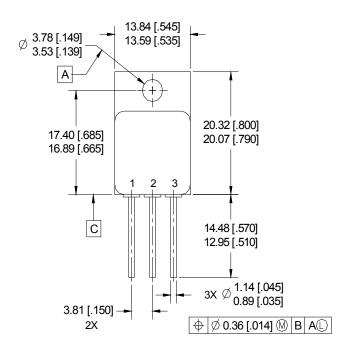
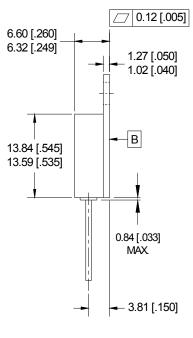


Fig 14b. Switching Time Waveforms



Case Outline and Dimensions — TO-254AA





NOTES:

- 1. DIMENSIONING & TOLERANCING PER ASME Y14.5M-1994.
- 2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
- 3. CONTROLLING DIMENSION: INCH.
- 4. CONFORMS TO JEDEC OUTLINE TO-254AA.

PIN ASSIGNMENTS

1 = DRAIN

2 = SOURCE

3 = GATE

BERYLLIA WARNING PER MIL-PRF-19500

Package containing beryllia shall not be ground, sandblasted, machined, or have other operations performed on them which will produce beryllia or beryllium dust. Furthermore, beryllium oxide packages shall not be placed in acids that will produce fumes containing beryllium.



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